

Description

The AP120N06P/T uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 65V I_{D} = 125A$

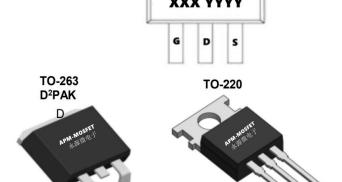
 $R_{DS(ON)} < 5.6 \text{m}\Omega$ @ $V_{GS}=10V$ (Type: $4.8 \text{m}\Omega$)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

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Product ID	Pack	Marking	Qty(PCS)
AP120N06P	TO-220-3L	AP120N06P XXX YYYY	1000
AP120N06T	TO-263-3L	AP120N06T XXX YYYY	800

Absolute Maximum Ratings@T_i=25°C(unless otherwise specified)

Symbol	Parameter	Value	Unit
VDS	Drain source voltage	65	V
VGS	Gate source voltage	±25	V
ID	Continuous drain current ¹⁾	125	А
IDM	Pulsed drain current ²⁾	492	А
IAS	Diode forward current	55	Α
P _D	Power dissipation	172	W
EAS	Single pulsed avalanche energy)	225	mJ
Tstg, Tj	Operation and storage temperature	-55 to 150	℃
RθJC	Thermal resistance, junction-case	1.4	°C/W
RθJA	Thermal resistance, junction-ambient ⁴⁾	62.5	°C/W



Electrical Characteristics (T_J=25°C, unless otherwise noted)

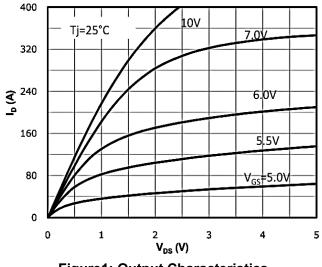
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	65	72	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V_{DS} = V_{GS} , I_D = $250\mu A$	2.0	2.8	4.0	V
RDS(on)	Static Drain-Source on-Resistance note	V _{GS} =10V, I _D =55A	-	4.8	5.6	mΩ
Ciss	Input Capacitance		-	3135	-	pF
Coss	Output Capacitance	V _{DS} =30V, V _{GS} =0V, f=1.0MHz	-	521	-	pF
Crss	Reverse Transfer Capacitance		-	306	-	pF
Qg	Total Gate Charge)/ 00)/ L 55A	1	77	-	nC
Qgs	Gate-Source Charge	V_{DS} =30V, I_D =55A, V_{GS} =10V	-	18	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	30	-	nC
td(on)	Turn-on Delay Time		1	15	-	ns
t _r	Turn-on Rise Time	V _{DS} =30V, I _D =55A,	-	89	-	ns
td(off)	Turn-off Delay Time	$R_G=1.8\Omega$, $V_{GS}=10V$	-	36	-	ns
t _f	Turn-off Fall Time		-	91	-	ns
IS	Maximum Continuous Drain to Source Diode ForwardCurrent		-	•	123	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		1	-	492	Α
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	L 550A WW 400A	-	32	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F =550A, dl/dt=100A/μs	-	31	-	nC

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- $2\sqrt{100}$ The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3. The test cond \leq 300us duty cycle \leq 2%, duty cycle ition is TJ =25°C, VDD =35V, VG =10V, R G =25 Ω , L=0.5mH, IAS =55A
- 4. The power dissipation is limited by 175 $\!\!\!\!^{\,\circ}\!\!\!\!^{\,\circ}$ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Electrical Characteristics Diagrams



400 V_{DS}=5V 320 V_{DS}=5V 320 160 150°C 25°C 25°C 25°C 80 25°C 80 25°C 80 Y_{GS} (V)

Figure1: Output Characteristics

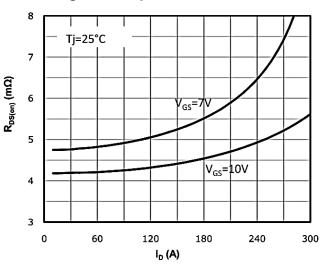


Figure 2: Typical Transfer Characteristics

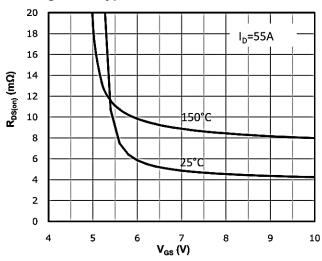


Figure 3: Rds(on) vs Drain Current and

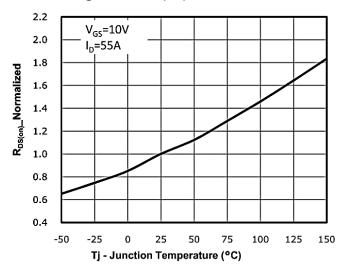


Figure 4: Rds(on) vs Gate Voltage

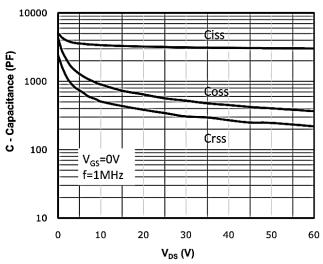
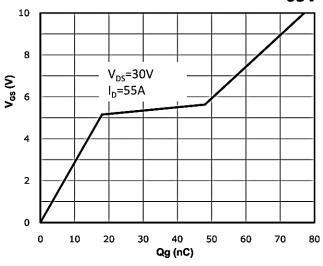


Figure 5: Rds(on) vs. Temperature

Figure 6: Capacitance Characteristics







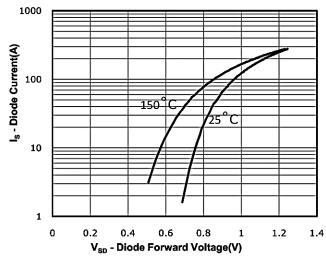


Figure 7: Gate Charge Characteristics

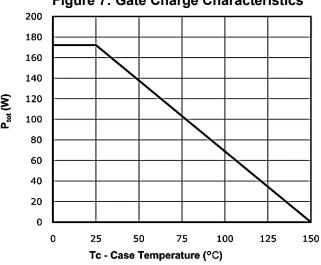


Figure 8: Body-diode Forward Characteristics

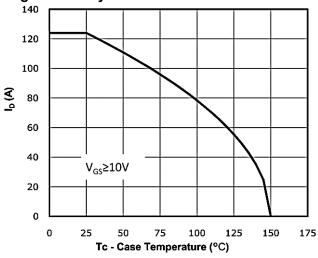


Figure 9: Power Dissipation



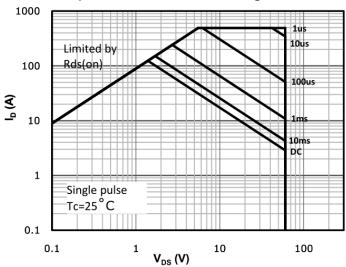
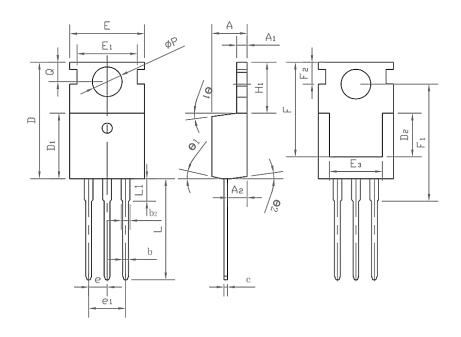


Figure.11: Safe Operating Area



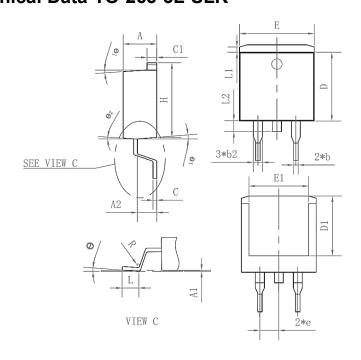
60V N-Channel Enhancement Mode MOSFET Package Mechanical Data-TO-220-3L-SLK



		Common		
Symbol		mm		
	Mim	Nom	Max	
Α	4.27	4.57	4.87	
A1	1.15	1.30	1.45	
A2	2.10	2.40	2.70	
b	0.70	0.80	1.00	
b2	1.17	1.27	1.50	
D	0.40	0.50	0.65	
D1	8.80	9.10	9.40	
D2	5.70	6.70	7.00	
E	9.70	10.00	10.30	
E1	-	8.70	-	
E2	9.63	10.00	10.35	
E3	7.00	8.00	8.40	
е		0.37		
e1		0.10		
H1	6.00	6.50	6.85	
L	12.75	13.50	13.90	
L1	-	3.10	3.40	
Фр	3.45	3.60	3.75	
Q	2.60	2.80	3.00	
θ1	4°	7°	10°	
θ2	0°	3°	6°	
F	13.30	13.50	13.70	
F1	15.50	15.90	16.30	
F2	2.80	3.00	3.20	



65V N-Channel Enhancement Mode MOSFET Package Mechanical Data-TO-263-3L-SLK



	Common mm		
Symbol			
-	Mim	Nom	Max
Α	4.35	4.47	4.60
A1	0.09	0.10	0.11
A2	2.30	2.40	2.70
b	0.70	0.80	1.00
b2	1.25	1.36	1.50
С	0.45	0.50	0.65
C1	1.29	1.30	9.40
D	9.10	9.20	9.30
D1	7.90	8.00	8.10
E	9.85	10.00	10.20
E1	7.90	8.00	8.10
Н	15.30	15.50	15.70
е	-	2.54	-
L	2.34	2.54	2.74
L1	1.00	1.10	1.20
L2	1.30	1.40	1.50
R	0.24	0.25	0.26
θ	0°	4°	8°
Θ1	4°	7°	10°
Θ2	0°	3°	6°



60V N-Channel Enhancement Mode MOSFET Attention

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AP120N06P/T

65V N-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2021/12/14	Initial release

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